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APPLICANT

RANDALL, Dr. Clive A, and Jonathan Van

Tassel

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**GROUP** 

(37 CFR 1.98(b))

## **U.S. PATENT DOCUMENTS**

Examiner Iniţial	Cite No. <sup>1</sup>	Patent Number	Issue Date	Patentee	Class/ Subclass	Filing Date
W/		4,130,472	Dec. 19, 1978	Kaplan, et. al.	204/181.N	Mar. 28, 1978
		4,357,222	Nov. 2, 1982	Lucek	204/181.F	Aug. 5, 1981
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W		5,415,748	May 16, 1995	Emiliani, et al.	204/181.5	Feb. 23, 1994

## FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

Examiner	Document	Publication	Country or Patent Office	Class/	Translation
Initial	Number	Date		Subclass	Yes/No

## OTHER DOCUMENTS

(Including Author, Title, Date, Relevant Pages, Place of Publication)

Examiner Initial	Cite No. <sup>1</sup>	
m		Herbert, J. M., CERAMIC DIELECTRICS AND CAPACITORS, 1985, pp. 78-83, 188-193.
		Adair, J.H., et al., A REVIEW OF THE PROCESSING OF ELECTRONIC CERAMICS WITH AN EMPHASIS ON MULTILAYER CAPACITOR FABRICATION, Journal of Materials Education, 1987, pp. 75-118.
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me)		Sarkar, Partho, et al., ELECTROPHORETIC DEPOSITION (EPD): MECHANISMS, KINETICS, AND APPLICATION TO CERAMICS, Journal of the American Ceramic Society, Vol. 79, No. 8, 1996, pp. 1987-2002.

EXAMINER	DATE CONSIDERED
MM	20101

EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considere Include copy of this form with next communication to applicant.